

**Search Notes**

Application/Control No.

10/511,792

Examiner

Chris C. Chu

Applicant(s)/Patent under  
Reexamination

RADENNE ET AL.

Art Unit

2815

**SEARCHED**

| Class | Subclass                        | Date      | Examiner |
|-------|---------------------------------|-----------|----------|
| 257   | E21.501,<br>E23.064 &<br>E23.14 | 9/17/2006 | C.C.     |
| 257   | 681                             | 9/17/2006 | C.C.     |
| 235   | 492                             | 9/17/2006 | C.C.     |
|       |                                 |           |          |
|       |                                 |           |          |
|       |                                 |           |          |
|       |                                 |           |          |
|       |                                 |           |          |
|       |                                 |           |          |
|       |                                 |           |          |
|       |                                 |           |          |
|       |                                 |           |          |
|       |                                 |           |          |
|       |                                 |           |          |

**INTERFERENCE SEARCHED**

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|  | DATE      | EXMR |
|--|-----------|------|
| Searched in<br>US-PGPUB; USPAT; USOCR; EPO;<br>JPO; DERWENT; FPRS; and<br>IBM_TDB; | 9/17/2006 | C.C. |
|  |           |      |
|  |           |      |
|  |           |      |
|  |           |      |
|  |           |      |
|  |           |      |
|  |           |      |
|  |           |      |
|  |           |      |
|  |           |      |
|  |           |      |
|  |           |      |